SN54BCT29828B, SN74BCT29828B 10-BIT BUFFERS/DRIVERS WITH 3-STATE OUTPUTS SCBS080B – DECEMBER 1990 – REVISED NOVEMBER 1993

 State-of-the-Art BiCMOS Design Significantly Reduces I_{CCZ}

- ESD Protection Exceeds 2000 V Per MIL-STD-883C, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- 3-State Inverting Outputs Drive Bus Lines or Buffer Memory Address Registers
- P-N-P Inputs Reduce dc Loading
- Flow-Through Architecture Optimizes PCB Layout
- Package Options Include Plastic Small-Outline (DW) Packages, Ceramic Chip Carriers (FK) and Flatpacks (W), and Standard Plastic and Ceramic 300-mil DIPs (JT, NT)

description

These 10-bit buffers and bus drivers provide high-performance bus interface for wide data paths or buses carrying parity.

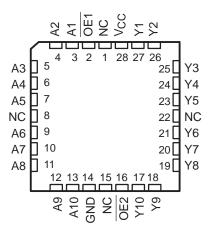
The 3-state control gate is a 2-input AND gate with active-low inputs so that if either output-enable $(\overline{OE1} \text{ or } \overline{OE2})$ input is high, all ten outputs are in the high-impedance state. The outputs are also in the high-impedance state during power-up and power-down conditions. The outputs remain in the high-impedance state while the device is powered down.

The SN54BCT29828B is characterized for operation over the full military temperature range of -55° C to 125° C. The SN74BCT29828B is characterized for operation from 0°C to 70°C.

SN74BCT29828B DW OR NT PACKAGE (TOP VIEW)									
OE1 [A1] A2 [A3] A4 [A5] A6 [A7] A8 [A9] GND [1 2 3 4 5 6 7 8 9 10 11 12	24 23 22 21 20 19 18 17 16 15 14	V _{CC} Y1 Y2 Y3 Y4 Y5 Y6 Y7 Y8 Y9 Y9 Y10						

SN54BCT29828B ... JT OR W PACKAGE

SN54BCT29828B . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

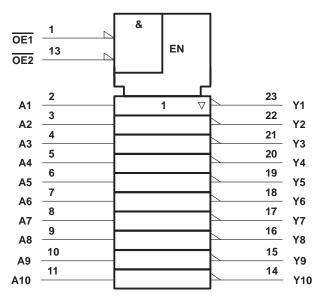
FUNCTION TABLE

	INPUTS	OUTPUT	
OE1	OE2	Α	Y
L	L	L	н
L	L	Н	L
н	Х	Х	Z
Х	Н	Х	Z

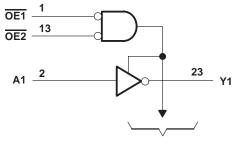
SN54BCT29828B, SN74BCT29828B 10-BIT BUFFERS/DRIVERS WITH 3-STATE OUTPUTS

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logic symbol[†]



logic diagram (positive logic)



To Nine Other Channels

[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for the DW, JT, NT, and W packages.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[‡]

Supply voltage range, V _{CC}		-0.5 V to 7 V
Input voltage range, V _I (see Note 1)		
Voltage range applied to any output in the		
Voltage range applied to any output in the		
Input clamp current, I _{IK} (V _I < 0)		
Current into any output in the low state, IO	SN54BCT29828B	
-	SN74BCT29828B	
Operating free-air temperature range:	SN54BCT29828B	–55°C to 125°C
	SN74BCT29828B	0°C to 70°C
Storage temperature range		–65°C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

recommended operating conditions

		SN54BCT29828B			SN74BCT29828B			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage	2			2			V
VIL	Low-level input voltage			0.8			0.8	V
Iк	Input clamp current			-18			-18	mA
ЮН	High-level output current	-15 -24		mA				
IOL	Low-level output current			24			48	mA
TA	Operating free-air temperature	-55		125	0		70	°C



SN54BCT29828B, SN74BCT29828B **10-BIT BUFFERS/DRIVERS** WITH 3-STATE OUTPUTS

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PARAMETER	ARAMETER TEST CONDITIONS		SN54	4BCT298	28B	SN74	LINUT		
PARAMETER	TES	ST CONDITIONS	MIN	түр†	MAX	MIN	TYP†	MAX	UNIT
VIK	V _{CC} = 4.5 V,	lj = -18 mA			-1.2			-1.2	V
		I _{OH} = -15 mA	2	3.2		2.4	3.3		
VOH	$V_{CC} = 4.5 V$	I _{OH} = - 24 mA				2	3.1		V
	V _{CC} = 4.75 V,	$I_{OH} = -3 \text{ mA}$				2.7			
Max		I _{OL} = 24 mA		0.38	0.55				V
VOL	$V_{CC} = 4.5 V$	I _{OL} = 48 mA					0.42	0.5	v
lj	V _{CC} = 5.5 V,	V _I = 7 V			0.1			0.1	mA
Iн	V _{CC} = 5.5 V,	V _I = 2.7 V			20			20	μA
۱ _{IL}	V _{CC} = 5.5 V,	V _I = 0.5 V			-0.2			-0.2	mA
Ios‡	V _{CC} = 5.5 V,	$V_{O} = 0$	-75		-250	-75		-250	mA
IOZH	V _{CC} = 5.5 V,	V _O = 2.7 V			20			20	μΑ
I _{OZL}	V _{CC} = 5.5 V,	V _O = 0.5 V			-20			-20	μΑ
ICCL	V _{CC} = 5.5 V,	Outputs open		28			28	40	mA
ICCH	V _{CC} = 5.5 V,	Outputs open		15			15	25	mA
ICCZ	V _{CC} = 5.5 V,	Outputs open		3.5			3.5	6	mA
Ci	$V_{CC} = 5 V,$	V _I = 2.5 V or 0.5 V		4.5			4.5		pF
Co	V _{CC} = 5 V,	V _O = 2.5 V or 0.5 V		7			7		pF

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

[†] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

[‡]Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

switching characteristics over recommended ranges of supply voltage and operating free-air temperature, $C_L = 50 \text{ pF}$ (unless otherwise noted) (see Note 2)

PARAMETER	FROM (INPUT)	TO (OUTPUT)			SN54BCT	29828B	SN74BCT	UNIT		
	(INPOT)	(001901)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	
^t PLH	А	v	1	3.3	5.2	1	6.3	1	5.9	ns
^t PHL		I	1	2.7	4.2	1	4.9	1	4.5	115
^t PZH	OE	V	2	5.3	7.7	2	9.2	2	8.6	200
^t PZL		T	2	8.5	10.2	2	12.7	2	11.9	ns
^t PHZ	ŌĒ	V	2	5.4	7.6	2	9.4	2	8.7	ns
t _{PLZ}		T	2	5.1	6.8	2	9	2	8.1	115

NOTE 2: Load circuits and voltage waveforms are shown in Section 1.



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